

Search Notes**Application/Control No.**

10/559,966

Examiner

Binh X. Tran

**Applicant(s)/Patent under
Reexamination**

IMADA ET AL.

Art Unit

1792

SEARCHED

Class	Subclass	Date	Examiner
216	11	6/27/2008	BT
216	40	6/27/2008	BT
216	44	6/27/2008	BT
216	53	6/27/2008	BT
216	83	6/27/2008	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR